

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				Atty. Docket No. SON-1854/SOH/DIV		Serial No. Unassigned (Div. of Appl. No. 09/787,036) 10/784,828	
				Applicant Akira YUMOTO			
				Filing Date February 24, 2004		Group: 2673	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
/L.L./		1-279670	11/09/89	JAPAN			Abstract
/L.L./		9-197313	07/31/97	JAPAN			Abstract
/L.L./		9-263810	10/07/97	JAPAN			Abstract
International Search Report							
EXAMINER /Lun Lao/				DATE CONSIDERED 06/01/2007			
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PTO/SB/08a/b (07-05)

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Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete if Known	
				Application Number	10/784,828-Conf. #9682
				Filing Date	February 24, 2004
				First Named Inventor	Akira Yumoto
				Art Unit	2871
				Examiner Name	L. Y. Lao
Sheet	1	of	1	Attorney Docket Number	SON-1854/DIV

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
/L.L./	AA*	US-6,359,605 B1	03-19-2002	Knapp et al.	
/L.L./	AB*	US-5,023,489	06-11-1991	Macbeth	
/L.L./	AC*	US-6,373,454	04-16-2002	Knapp et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ²
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				
/L.L./	BA	WO-98/48403	10-29-1998	SARNOFF CORPORATION		
	BB	JP-10-319908	12-04-1998			
	BC	WO-99/65012	12-16-1999	PHILIPS AB		
	BD	WO-99/65011	12-16-1999	PHILIPS AB		
	BE	JP-11-282419	10-15-1999	NEC Corporation		
/L.L./	BF	EP-0 397 253	11-14-1990	PHILIPS ELECTRONIC AND ASSOCIATED IND LTD		

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NON PATENT LITERATURE DOCUMENTS					
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/L.L./	CA	DAWSON R M A et al.: "The Impact of the Transient Response of Organic Light Emitting Diodes on the Design of Active Matrix Oled Display," Internation Electron Devices Meetin 1998. IEDM Technical Digest. San Francisco, CA, December 6-9, 1998, New York, NY: IEEE, US, 6 December 1998 (1998-12-06), pages 875-878, XP000859508			
/L.L./	CB	Supplementary Partial European Search Report; Application No.: EP 00 94 6353; dated June 12, 2006			

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